

<b>Notice of References Cited</b>	Application/Control No. 10/725,529	Applicant(s)/Patent Under Reexamination OHIGASHI ET AL.	
	Examiner Leslie J. Evanisko	Art Unit 2854	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,373,218	04-2002	Takanashi et al.	318/568.21
	B	US-2003/0159607	08-2003	Nitzan et al.	101/466
	C	US-6,143,158	11-2000	Nishino et al.	205/219
	D	US-2003/0167950	09-2003	Mori, Takahiro	101/453
	E	US-2002/0051931	05-2002	MORI et al.	430/270.1
	F	US-6,354,209	03-2002	Van Aert et al.	101/466
	G	US-6,341,560	01-2002	Shah et al.	101/463.1
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0 503 621 A1	09-1992	EPO	Hase et al.	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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